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### 1 A new approach to evaluation of hot-carrier lifetime of ring oscillator (RO)

Jiong Zhang; Chu, S.-F.S.;

Electron Devices, IEEE Transactions on, Volume: 49, Issue: 9, Sept. 2002

Pages:1672 - 1674

[Abstract] [PDF Full-Text (226 KB)] IEEE JNL

### 2 AC hot-carrier degradation in a voltage controlled oscillator

Jiang, C.; Johnson, E.; Shaw, J.J.; Hu, C.;

Reliability Physics Symposium, 1993. 31st Annual Proceedings., International, 23-25 March 1993

Pages:53 - 56

[Abstract] [PDF Full-Text (192 KB)] IEEE CNF

### 3 Effects of hot-carrier stress on the performance of the LC-tank CMOS oscillators

Naseh, S.; Deen, M.J.; Marinov, O.;

Electron Devices, IEEE Transactions on, Volume: 50, Issue: 5, May 2003

Pages:1334 - 1339

[Abstract] [PDF Full-Text (387 KB)] IEEE JNL

### 4 Hot-carrier and soft-breakdown effects on VCO performance

Enjun Xiao; Yuan, J.S.; Hong Yang;

Microwave Theory and Techniques, IEEE Transactions on, Volume: 50, Issue: 11, Nov. 2002

Pages:2453 - 2458

[Abstract] [PDF Full-Text (449 KB)] IEEE JNL

### 5 RF circuit performance degradation due to hot carrier effects and soft breakdown

*Enjun Xiao; Yuan, J.S.;*  
Circuits and Systems, 2002. MWSCAS-2002. The 2002 45th Midwest Symposium on , Volume: 1 , 4-7 Aug. 2002  
Pages:I - 17-20 vol.1

[\[Abstract\]](#) [\[PDF Full-Text \(308 KB\)\]](#) IEEE CNF

#### 6 Hot carrier and soft breakdown effects on VCO performance

*Enjun Xiao; Yuan, J.S.;*  
Radio Frequency Integrated Circuits (RFIC) Symposium, 2002 IEEE , 2-4 June 2002  
Pages:459 - 462

[\[Abstract\]](#) [\[PDF Full-Text \(523 KB\)\]](#) IEEE CNF

#### 7 Comparison of calculated AC to DC Hot Carrier lifetimes based on combined single MOST DC stress results and inverter simulations with AC stress measurements on single MOST's to check the duty factor approach

*Kuge, H.-H.;*  
Integrated Reliability Workshop Final Report, 2002. IEEE International , 21-24 Oct. 2002  
Pages:188 - 191

[\[Abstract\]](#) [\[PDF Full-Text \(385 KB\)\]](#) IEEE CNF

#### 8 Evaluation of oscillator phase noise subject to reliability

*Enjun Xiao; Yuan, J.S.;*  
Frequency Control Symposium and PDA Exhibition Jointly with the 17th European Frequency and Time Forum, 2003. Proceedings of the 2003 IEEE International , 4-8 May 2003  
Pages:565 - 568

[\[Abstract\]](#) [\[PDF Full-Text \(307 KB\)\]](#) IEEE CNF

#### 9 RF circuit design in reliability

*Enjun Xiao; Yuan, J.S.;*  
Microwave Symposium Digest, 2003 IEEE MTT-S International , Volume: 1 , 8-13 June 2003  
Pages:A61 - A64 vol.1

[\[Abstract\]](#) [\[PDF Full-Text \(332 KB\)\]](#) IEEE CNF

#### 10 Hot carrier and soft breakdown effects on VCO performance

*Xiao, E.; Yuan, J.S.;*  
Microwave Symposium Digest, 2002 IEEE MTT-S International , Volume: 1 , 2-7 June 2002  
Pages:569 - 572

[\[Abstract\]](#) [\[PDF Full-Text \(527 KB\)\]](#) IEEE CNF

#### 11 CMOS RF: (still) no longer an oxymoron

*Lee, T.H.;*  
Radio Frequency Integrated Circuits (RFIC) Symposium, 1999 IEEE , 13-15 June 1999  
Pages:3 - 6

[\[Abstract\]](#) [\[PDF Full-Text \(340 KB\)\]](#) IEEE CNF

---

**12 Low power RFICs for receiver applications - design and performance issues***Deen, M.J.; Naseh, S.; Wai Leung Ngan; Jafferli, N.;*

Electron Devices and Solid-State Circuits, 2003 IEEE Conference on , 16-18 Dec. 2003

Pages:215 - 220

[\[Abstract\]](#) [\[PDF Full-Text \(465 KB\)\]](#) [IEEE CNF](#)

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**13 Application of hot-carrier reliability simulation to memory and ASIC design***Lee, P.M.; Sato, H.;*

Solid-State and Integrated-Circuit Technology, 2001. Proceedings. 6th International Conference on , Volume: 2 , 22-25 Oct. 2001

Pages:1112 - 1117 vol.2

[\[Abstract\]](#) [\[PDF Full-Text \(307 KB\)\]](#) [IEEE CNF](#)

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**14 Enhanced degradation of nMOSFET's under hot carrier stress at elevated temperatures due to the length of velocity saturation region***Hyunsang Hwang; Jung-Suk Goo; Hoyup Kwon; Hyungsoon Shin;*

Integrated Reliability Workshop, 1994. Final Report., 1994 International , 16-19 Oct. 1994

Pages:69 - 72

[\[Abstract\]](#) [\[PDF Full-Text \(272 KB\)\]](#) [IEEE CNF](#)

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**15 AC hot-carrier degradation in the super-100 MHz operation range***Yoshida, S.; Matsui, T.; Okuyama, K.; Kubota, K.;*

VLSI Technology, 1994. Digest of Technical Papers. 1994 Symposium on , 7-9 June 1994

Pages:145 - 146

[\[Abstract\]](#) [\[PDF Full-Text \(156 KB\)\]](#) [IEEE CNF](#)

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